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- (71) **Applicant** (*for all designated States except US*):
TERAVIEW LIMITED [GB/GB]; Platinum Building, St John's Innovation Park, Cambridge, Cambridgeshire CB4 0WS (GB).
- (72) **Inventor; and**
- (75) **Inventor/Applicant** (*for US only*): **COLE, Bryan Edward** [GB/GB]; c/o TeraView Limited, Platinum Building, St John's Innovation Park, Cambridge, Cambridgeshire CB4 0WS (GB).
- (74) **Agent:** **GRANLEESE, Rhian**; 90 Long Acre, London WC2E 9RA (GB).

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(54) **Title:** A TEST SYSTEM

(57) **Abstract:** A reflectometer for allowing a test of a device, the reflectometer comprising: a source of pulsed radiation; a first photoconductive element configured to output a pulse in response to irradiation from said pulsed source; a second photoconductive element configured to receive a pulse; a transmission line arrangement configured to direct the pulse from the first photoconductive element to the device under test and to direct the pulse reflected from the device under test to the second photoconductive element; and a termination resistance provided for said transmission line configured to match the impedance of the transmission line.



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